


<b>Search Notes</b>  	<b>Application/Control No.</b>  10754174	<b>Applicant(s)/Patent Under Reexamination</b>  LAU ET AL.
	<b>Examiner</b>  John P Lacyk	<b>Art Unit</b>  3735

SEARCHED			
Class	Subclass	Date	Examiner
600	16, 37	2/22/05	NV
36	50.1, 110	2/22/05	NV
385	100, 105	2/22/05	NV
24	387	2/22/05	NV
Updated	above	3/27/08	JPL
Updated	above	5/23/08	JPL

SEARCH NOTES		
Search Notes	Date	Examiner
Inventorship	2/22/05	NV
East	2/22/05	NV
West	2/22/05	NV
Consulted with Ex. S. Gilbert	2/22/05	NV

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
Interference Search History Printout		5/27/08	JPL